## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | LEE ET AL. | Examiner | Art Unit | David J. Makiya | 2885 | Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0163001 A1	11-2002	Shaddock, David Mulford	257/79
*	В	US-6,707,069 B2	03-2004	Song et al.	257/79
*	O	US-2004/0140765 A1	07-2004	Takekuma, Akira	313/512
*	۵	US-2004/0240203 A1	12-2004	Matsumura et al.	362/227
*	ш	US-2004/0256630 A1	12-2004	Cao, Densen	257/098
	F	US-			,
	G	US-			
	H	US-			
	1	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	T					

## **NON-PATENT DOCUMENTS**

	NOW ALEN BOOMENTO					
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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	v					
	w					
	x					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.